

<b>Notice of References Cited</b>	Application/Control No. 10/758,808	Applicant(s)/Patent Under Reexamination VANG ET AL.	
	Examiner Tuyen Q Tra	Art Unit 2873	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,836,351 B2	12-2004	Livingston et al.	359/279
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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	N					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Cartledge, J.C., "Comparision of effective alpha-parameters for semiconductor Mach-Zehnder optical modulators," Mar. 1998, pp. 372-379, Journal of Lightwave Technology, Vol. 16, No. 3.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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